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INFORMATION REPORT

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DATE DISTR. 15 March 1954 COUNTRY East Germany SUBJECT NO. OF PAGES Exposure Device for X-Ray Intensity Wedge 25X1 PLACE ACQUIRED SUPPLEMENT TO REPORT NO. DATE OF THIS IS UNEVALUATED INFORMATION 25X1 Research work in the Department for Crystal Structure Analysis of the Academy Institute for Medicine and Biology in Berlin-Buch has been 25X1 hampered by the lack of an adequate method for determining the intensity of defraction spots (called "reflexes" in Buch_terminology) 25X1 in the X-ray film of a crystal. this shortcoming is a serious handicap for crystal research analysis quite generally and 25X1 prevails everywhere. So far, determination of the intensity had to be carried out by visual estimate, and this procedure involved a margin of error of from five to thirty percent. While the relatively 25X1 small error of five percent is attainable at the beginning of an observation it gradually increases to thirty percent as a result of fatigue caused by long observation time. 25X12 · development of a device which is supposed to eliminate to a great extent the error due to subjective estimate. The device is called "The Exposure Device for a▶ X-Ray Intensity Wedge" (Belichtungsgeraet fuer Roentgenintensitaetskeil); construction plans for the device were finished in late November 1953. With the aid of this device and an evaluation device, 25X1 expects to reduce the margin of error in the determination of X-ray intensity to plus minus 0.5 percent. The Exposure Device works in the following way: The device is provided with a dark-slide (Kassette) into which the X-ray film of a crystal is introfucced The dark-slide has two diaphragms which can be closed and opened by means of two slides. The diaphragms are exposed to an X-ray source after the slides are opened. By totating the diaphragmatwo black "wedges" are produced on the X-ray film of the crystal. position of the diaphragms is such that the blackening of the X-ray film only takes place on the margin of the film, so that the X-ray picture of the crystal is not disturbed. The black "wedges" are not uniformly black, but have different shades of blackness. With the aid of the evaluation device yet to be developed t will be possible to compare the intensities of the diffraction spots with the "wedges" and express them in exact figures. The dark-slide is protected by a sheet

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of lead against the X-ray source, so that direct exposure and exposure to scattered rays is impossible. The dimensions of the dark-slide have been selected so that films of several types of X-ray cameras, such as the Weissenberg and De Jong cameras, can be inserted.

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25X1	of the Institute for Medicine and Biology.	
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In addition to the considerably increased accuracy in the determination of intensities, the following advantages will result from the device

 a. Determination of intensities can be performed by non-expert, auxiliary personnel;

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b. Duration of the evaluation of an X-ray picture will be reduced by about eighty percent.

5. The complete device, including the evaluation device, is supposed to be in operating order by the end of 1954.

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